



University of Pennsylvania  
**ScholarlyCommons**

---

Tool Data

[Browse by Type](#)

---

6-13-2015

# Thickness Measurement on Ti, Au, Pd, and Cr using PVD75 E-beam Evaporator

Dhruv Turakhia  
[tdhruv@seas.upenn.edu](mailto:tdhruv@seas.upenn.edu)

Follow this and additional works at: [http://repository.upenn.edu/scn\\_tooldata](http://repository.upenn.edu/scn_tooldata)

---

Turakhia, Dhruv, "Thickness Measurement on Ti, Au, Pd, and Cr using PVD75 E-beam Evaporator", *Tool Data*. Paper 30.  
[http://repository.upenn.edu/scn\\_tooldata/30](http://repository.upenn.edu/scn_tooldata/30)

This paper is posted at ScholarlyCommons. [http://repository.upenn.edu/scn\\_tooldata/30](http://repository.upenn.edu/scn_tooldata/30)  
For more information, please contact [libraryrepository@pobox.upenn.edu](mailto:libraryrepository@pobox.upenn.edu).

---

# Thickness Measurement on Ti, Au, Pd, and Cr using PVD75 E-beam Evaporator

## **Keywords**

Thickness, Ti, Au, Pd, Cr

## **Creative Commons License**



This work is licensed under a [Creative Commons Attribution-Share Alike 4.0 License](https://creativecommons.org/licenses/by-sa/4.0/).

# Thickness Measurement on Ti, Au, Pd, and Au using PVD75 E-beam Evaporator (Graduate Student Fellow Program)

Prepared by Dhruv Turakhia (6/5/2015)

Deposition Rate: 2 Å/sec

Final Thickness Set Point: 300 nm

Default Tooling Factor Xtal 1: 54

Default Tooling Factor Xtal 2: 100

Thickness measurement: P7 Stylus Profiler

## **Ti deposition**

Measured thickness:  $306.0 \pm 9.6$  nm

## **Au deposition**

Measured thickness:  $237.6 \pm 4.2$  nm

## **Pd deposition**

Measured thickness:  $265.5 \pm 17.8$  nm

## **Cr deposition**

Measured thickness:  $407.2 \pm 16.5$  nm